

Signal processing and the Software Support for Metrology programme: helping ensure good practice in metrology applications

T J Esward

Mathematics and Scientific Computing Group

Enabling Metrology Division, NPL

30th November 2005

This talk is about:

- **Introducing the Software Support for Metrology (SSfM) programme**
- **How signal processing became part of DTI's SSfM programme – SSfM2 New Directions study.**
- **Why metrologists need a guide to good practice in DSP**
- **How today's event will work**

Mathematics and Scientific Computing Group

- **Mathematics and Scientific Computing Group (MSCG) has 16 Mathematicians, Statisticians, Software Engineers and Physicists**
- **Part of the Division of Enabling Metrology**
- **We support all areas of metrology in other NPL Divisions & NMS programmes**
- **Our own NMS programme is Software Support for Metrology (SSfM)**
- **We also do 3rd party work**

Software Support for Metrology programme (SSfM)

- **The Software Support for Metrology programme is worth £3.1m over 3 years**
- **SSfM covers metrology, mathematics, statistics and software**
- **We develop and promote best/good practice in the application of mathematics and software to metrology**
- **We support NMS programmes, industry & public sector**
- **We provide generic solutions**

The programme has four main technological themes

- **Modelling tools and techniques**
- **Uncertainties and statistical techniques**
- **Software development, testing and validation**
- **Applications and supporting techniques**

SSfM-3 has a number of new topics

- **Supporting metrologists in signal processing, filtering and feature detection**
- **Establishing good practice in grid and distributed computing systems**
- **Modelling to support nanotechnology**
- **New Good Practice Guide on continuous modelling**
- **Interfaces for enabling Internet metrology**

SSfM-2 New Directions study questions

- **What do metrologists know?**
- **What do they need to know?**
- **Do they understand their own limitations?**
- **How can SSfM help?**
- **Study available on NPL web site:
http://www.npl.co.uk/ssfm/download/download.php?name=documents/cmssc17_03.pdf**

Signal processing: new topic in SSfM-3

- **Develop a Good Practice Guide for metrologists**
- **Case studies in different metrology areas**
- **Specific guidance on techniques for filtering and feature detection, including non-stationary signals and wavelets**

DSP requirements in metrology

- **Data analysis involves three stages: acquisition, processing, interpretation.**
- **First two stages introduce artefacts in raw unprocessed data that may be observed in third stage**
- **Important to understand how signal conditioning and processing affect original data: “improving” the data may introduce errors**

Categories of signal

- **Deterministic**
 - **Periodic**
 - **Non-periodic (transient and ‘almost’ periodic)**
- **Random (not predictable exactly)**
 - **Stationary (e.g white noise)**
 - **Non-stationary**
- **In reality processes may be mixed and required analysis procedure may not be obvious**

Fundamentals of digitised data

- **Two processes: sampling and quantisation**
- **Sampling converts analogue signal into a discrete signal**
- **Quantisation turns discrete signal into binary data**
- **Metrologists need to understand errors arising from sample-and-hold circuits and from quantisation**

Today's event

- **Learn about and share experiences in signal processing in metrology**
- **Identify material and suitable approach for the Good Practice Guide**
- **Guide is due March 2007**
- **We need your help in identifying and “calibrating” what should be in the Guide**

Seminar questionnaire

- **You are NOT being asked to comment on the speaker's style or delivery, only on the technical level as you perceived it**
- **Was the talk the right length for you, was it at the right technical level, was there enough detail?**
- **We need your replies to help us in drafting the Good Practice Guide**
- **Panel discussion at end of day allows more general debate about content of day's events**

Software demonstrations

- **Jonathan Williams, LabVIEW for remote capture and analysis of signals**
- **Pierre Gélat, Monte Carlo analysis of uncertainties in deconvolution**
- **Patrick Gaydecki, applications and systems for DSP**